TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 4 8 3 9

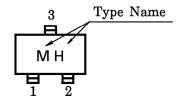
VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

- Low Noise Figure, High Gain.
- NF=1.1dB, $|S_{21e}|^2 = 12dB$ (f=1GHz)

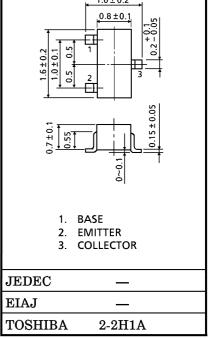
MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	20	V
Collector-Emitter Voltage	v_{CEO}	12	V
Emitter-Base Voltage	v_{EBO}	3	V
Collector Current	$I_{\mathbf{C}}$	80	mA
Base Current	$I_{\mathbf{B}}$	40	mA
Collector Power Dissipation	PC	100	mW
Junction Temperature	T_{j}	125	°C
Storage Temperature Range	$\mathrm{T}_{\mathrm{stg}}$	-55~125	°C

Marking



Unit in mm



Weight: 2.4mg

MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Transition Frequency	$ m f_{T}$	$V_{CE}=10V, I_{C}=20mA$	5	7	_	GHz	
Insertion Gain	$ S_{21e} ^2$ (1)	$V_{CE} = 10V, I_{C} = 20mA, f = 500MHz$	_	18	_	dB	
	$ S_{21e} ^2$ (2)	$V_{CE}=10V$, $I_{C}=20mA$, $f=1GHz$	7.5	12	_		
Naisa Eiguna	NF (1)	$V_{CE}=10V$, $I_{C}=5mA$, $f=500MHz$	_	1	_	dB	
Noise Figure	NF (2)	V_{CE} =10V, I_{C} =5mA, f =1GHz	_	1.1	2	ub	

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	ICBO	$V_{CB} = 10V, I_{E} = 0$	_	_	1	μ A
Emitter Cut-off Current	I_{EBO}	$V_{EB}=1V, I_{C}=0$	_	_	1	μ A
DC Current Gain	${ m h_{FE}}$	$V_{CE} = 10V, I_{C} = 20mA$	30	_	250	_
Output Capacitance	C_{ob}	$V_{CB} = 10V, I_E = 0, f = 1MHz$	_	0.85	_	pF
Reverse Transfer Capacitance	$\mathrm{c_{re}}$	(Note)	_	0.6	1.15	PF

(Note) C_{re} is measured by 3 terminal method with capacitance bridge.

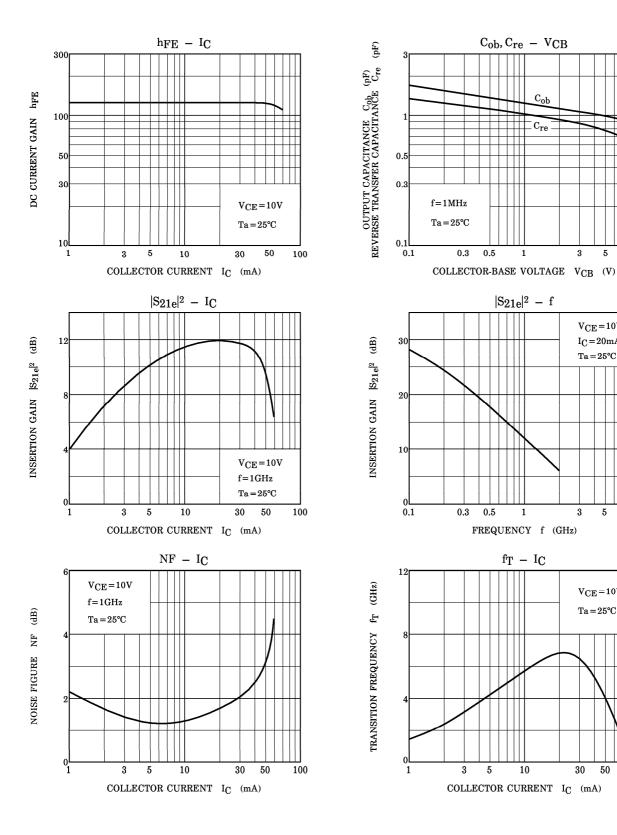
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 $V_{\text{CE}}\!=\!10V$ $I_{\hbox{\scriptsize C}}\!=\!20\hbox{\scriptsize mA}$

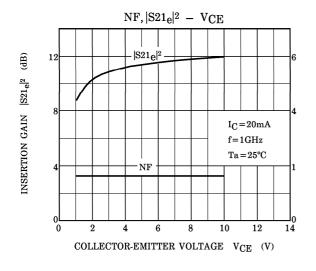
 $Ta = 25^{\circ}C$

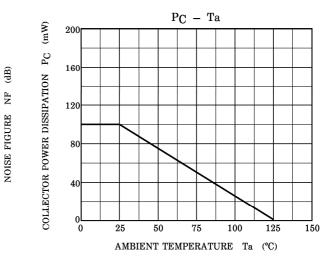
 $v_{CE}\!=\!\mathtt{10}v$

 $\mathrm{Ta} = 25^{\circ}\mathrm{C}$



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S-PARAMETER $Z_O = 50\Omega$, $T_a = 25^{\circ}C$ $V_{CE} = 10V$, $I_C = 5mA$

FREQUENCY	JENCY S11		S21		S12		S22	
MHz	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
200	0.705	-67.0	9.702	132.700	0.048	57.9	0.769	-27.9
400	0.536	-109.6	6.665	109.300	0.066	50.8	0.591	-34.7
600	0.467	-135.0	4.880	96.100	0.077	52.3	0.518	-36.9
800	0.440	-151.6	3.799	87.500	0.088	56.2	0.486	-39.0
1000	0.426	-164.9	3.136	80.600	0.100	60.3	0.475	-415
1200	0.417	-175.0	2.668	75.000	0.113	64.2	0.469	-44.5
1400	0.412	176.5	2.349	69.800	0.129	67.6	0.469	-47.8
1600	0.405	169.0	2.099	65.100	0.147	70.4	0.470	-51.2
1800	0.399	162.8	1.916	61.100	0.168	72.2	0.474	-54.1
2000	0.393	157.9	1.777	56.900	0.190	73.5	0.474	-57.8

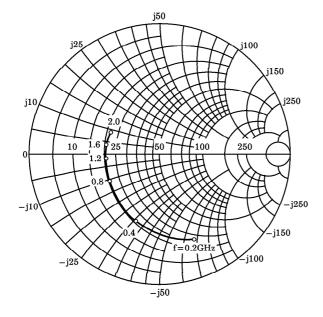
 $V_{CE} = 10V, I_{C} = 20mA$

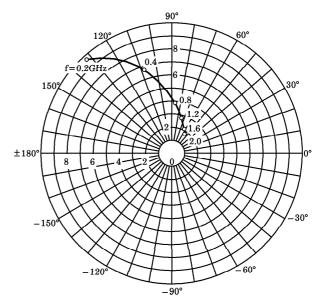
FREQUENCY S11		811	S21		S12		S22	
MHz	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
200	0.416	-111.00	16.818	111.100	0.032	61.30	0.504	-36.4
400	0.352	-145.90	9.121	95.900	0.051	67.10	0.382	-34.9
600	0.343	-163.20	6.289	87.800	0.070	70.90	0.352	-34.7
800	0.341	-174.70	4.772	81.800	0.090	72.80	0.342	-36.3
1000	0.341	-175.50	3.903	76.400	0.111	73.70	0.341	-39.2
1200	0.338	167.80	3.294	72.300	0.132	73.90	0.346	-41.9
1400	0.333	160.90	2.898	67.800	0.154	73.90	0.349	-45.8
1600	0.325	154.60	2.563	63.800	0.176	73.60	0.355	-49.0
1800	0.314	150.30	2.322	60.300	0.200	72.90	0.361	-51.9
2000	0.301	147.30	2.132	56.600	0.223	72.10	0.363	-55.0

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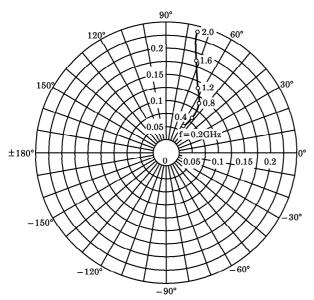
 $\begin{array}{l} S_{11e} \\ V_{CE} = 10V \\ I_{C} = 5 mA \\ Ta = 25 ^{\circ}C \\ (UNIT:\Omega) \end{array}$

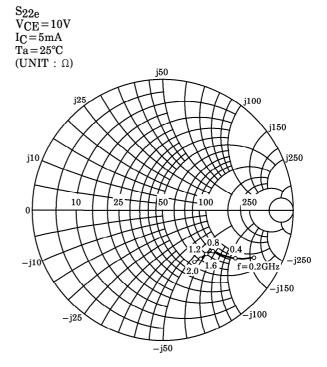






 $\begin{array}{l} S_{12e} \\ V_{CE} \!=\! 10V \\ I_{C} \!=\! 5 \mathrm{mA} \\ Ta \!=\! 25 ^{\circ}\! \mathrm{C} \end{array}$





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j250

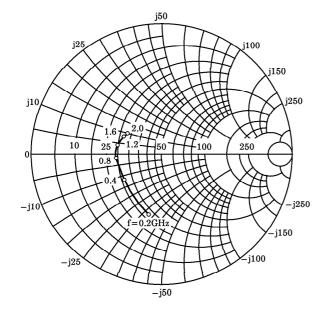
-j250

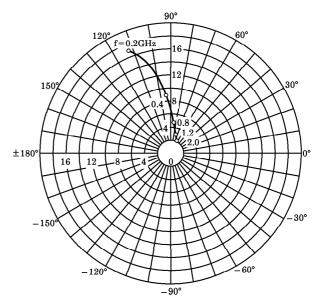
-j150

-j100

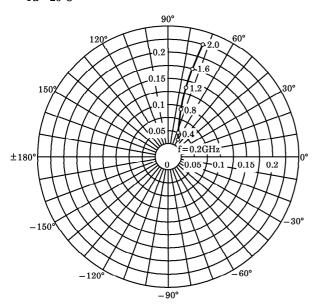
 $\begin{array}{l} S_{11e} \\ V_{CE} = 10V \\ I_{C} = 20 mA \\ Ta = 25 ^{\circ}C \\ (UNIT:\Omega) \end{array}$







 $\begin{array}{l} S_{12e} \\ V_{CE} \! = \! 10V \\ I_{C} \! = \! 20mA \\ Ta \! = \! 25^{\circ}\! C \end{array}$



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-j50

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